



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Inventors: Jiping Li; Peter G. Borden; Edgar B. Genio  
Assignee: Applied Materials, Inc.  
Title: High Throughput Measurement Of Via Defects In Interconnects  
Serial No.: 10/813,407 Filing Date: March 29, 2004  
Examiner: Trinh, Michael Manh Group Art Unit: 2822  
Docket No.: BOX016 US Confirmation No: 5642

Santa Clara, California  
September 6, 2005

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**SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT**

Dear Sir:

Pursuant to 37 C.F.R. § 1.56, §1.97 and §1.98, the Applicants submit for consideration in the above-identified patent application the documents listed on the accompanying Form PTO-1449. Copies of documents numbered 121-125 are also submitted herewith. The remaining documents are not attached hereto, because these documents are issued patents or publications which are readily available in the U.S. Patent and Trademark Office. The Examiner is requested to make all of the listed documents of record. Applicants would appreciate the Examiner initialing and returning the Form PTO-1449, indicating that the information has been considered and made of record herein.

Item 125 identified in the attached PTO-1449 is a partial International Search Report (ISR) in a PCT application which claims priority from the current application. Note also that the attached partial ISR (item 125) cites items 113-115 in the attached PTO-1449 and item 19 in an earlier PTO-1449 filed on March 25, 2005. In that earlier PTO-1449 Applicants also listed two prosecution histories as items 97 and 101, which contain the two items marked "X" in the attached partial ISR (item 125).

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This Information Disclosure Statement is submitted after receipt of a restriction requirement but before a first Office Action on the merits. Accordingly, no fee should be required. If a fee is required, please charge the deposit account 50-2263 and identify the charge by using the docket number BOX016 US.

The information contained in this Supplemental Information Disclosure Statement is to the best of my knowledge and is not to be construed as a representation that: (i) a complete search has been made; (ii) additional information material to the examination of this application does not exist; (iii) the information, protocols, results and the like reported by third parties are accurate or enabling; or (iv) the above information constitutes prior art to the subject invention.

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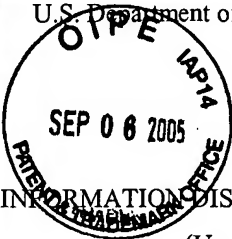
Respectfully submitted,



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|  <p>U.S. Department of Commerce, Patent and Trademark Office</p> <p>INFORMATION DISCLOSURE STATEMENT BY APPLICANT</p> <p>(Use several sheets if necessary)</p> | Application No.:      | 10/813,407     |
|  | Filing Date:          | March 29, 2004 |
|  | First Named Inventor: | Jiping Li      |
|  | Group Art Unit:       | 2822           |
|  | Examiner Name:        | Trinh          |
|  | Confirmation No.:     | 5642           |
|  | Attorney Docket No.:  | BOX016 US      |

| U.S. Patent Documents  |     |   |          |                 |       |          |                               |
|--|-----|---|----------|-----------------|-------|----------|-------------------------------|
| *Examiner<br>Initials  |     | Document Number   | Date     | Name            | Class | Subclass | Filing Date if<br>Appropriate |
|  | 107 | 6,040,936   | 3/21/01  | Kim et al.      | 359   | 245      |                               |
|  | 108 | 6,720,248   | 4/13/04  | Ryo             | 438   | 622      |                               |
|  | 109 | 6,747,355   | 6/8/04   | Abiru           | 257   | 758      |                               |
|  | 110 | 4,873,434   | 10/10/89 | See et al.      | 250   | 235      |                               |
|  | 111 | 6,541,747 B1  | 4/1/03   | Kikuchi et al.  | 250   | 201      |                               |
|  | 112 | 2002/0167326 A1   | 11/14/02 | Borden et al.   | 324   | 752      |                               |
|  | 113 | 2003/0165178 A1   | 9/4/03   | Borden et al.   | 374   | 5        |                               |
|  | 114 | 6,387,715   | 5/14/02  | David et al.    | 438   | 16       |                               |
|  | 115 | 2001/0017878 A1   | 8/30/01  | Nozoe et al.    | 374   | 7        |                               |
|  | 116 | 6,330,361   | 12/11/01 | Mitchell et al. | 382   | 211      |                               |
|  | 117 | 4,201,087   | 5/6/80   | Akita et al.    | 73    | 339      |                               |
|  | 118 | 6,178,020   | 1/23/01  | Schultz et al.  | 359   | 107      |                               |
|  | 119 | 5,128,864   | 7/7/92   | Waggener et al. | 364   | 413      |                               |
|  | 120 | 5,304,931   | 4/19/94  | Flamig et al.   | 324   | 309      |                               |
| Other Art (Including Author, Title, Date, Pertinent Pages, Etc.) |     |   |          |                 |       |          |                               |
|  | 121 | J.M. Ziman, F.R.S., "Principles of the Theory of Solids", 2nd Edition, Cambridge At the University Press 1972, pp 278-282   |          |                 |       |          |                               |
|  | 122 | Chung Wah See and Mehdi Vaez-Iravani, "Differential amplitude scanning optical microscope: theory and applications", Applied Optics Vol. 27, No. 13, July 1, 1988, pp 2786-2792 |          |                 |       |          |                               |
|  | 123 | International Search Report in PCT/US03/06250 which claims priority of US Application 10/090,287  |          |                 |       |          |                               |
|  | 124 | Written Opinion in PCT/US99/12999 which claims priority of US Application 09/095,805  |          |                 |       |          |                               |
|  | 125 | Communication Relating To Results of Partial International Search in PCT/US05/009588, which claims priority of US Application 10/813,407 ( <i>current application</i> )         |          |                 |       |          |                               |
|  |     |   |          |                 |       |          |                               |

|  |                  |
|--|------------------|
| Examiner:  | Date Considered: |
| <p>* Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with your communication with applicant.</p> |                  |